

PointProbe® Plus Contact Mode - Au Coating (Detector side)

The PointProbe® Plus (PPP) combines high application versatility and compatibility with most commercial SPMs. The typical AFM tip radius of less than 7 nm and the minimized variation in AFM tip shape provide reproducible images and enhanced resolution.

NANOSENSORS™ PPP-CONTAuD probes are designed for contact mode (repulsive mode) AFM imaging. This AFM probe can also be used for force-distance spectroscopy mode or pulsed force mode (PFM). The CONT type is optimized for high sensitivity due to a low force constant.

The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 10 nm
- AFM tip height 10 - 15 µm
- highly doped silicon to dissipate static charge
- Au coating on detector side of AFM cantilever
- chemically inert

A metallic layer (Au) is coated on the detector side of the AFM cantilever which enhances the reflectivity of the laser beam by a factor of about 2.5. Furthermore it prevents light from interfering within the AFM cantilever. As the coating is nearly stress-free the bending of the AFM cantilever due to stress is less than 2 degrees.

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	13	6 - 21
Force Constant [N/m]	0.2	0.02 - 0.77
Length [µm]	450	440 - 460
Mean Width [µm]	50	42.5 - 57.5
Thickness [µm]	2	1 - 3

Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PPP-CONTAuD-10	10	of all probes